

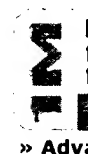
Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	15486	(three adj dimension\$2 or 3D)and(ball adj grid adj array or BGA or terminals or lead\$2)and inspect\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/18 12:13
L2	0	(three adj dimension\$2 or 3D)and(ball adj grid adj array or BGA or terminals or lead\$2)and inspect\$3 and single near3(camera or ccd or detector\$1 or sensor\$1)with (two adj mirrors or two adj lenses or two adj optical adj elements)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/18 12:15

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```
(three <near/5> dimensional
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<near/3> array or bga or
leads or terminals)and single
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